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WISBAL 實驗室成員回娘家
之經驗交流與回顧分享

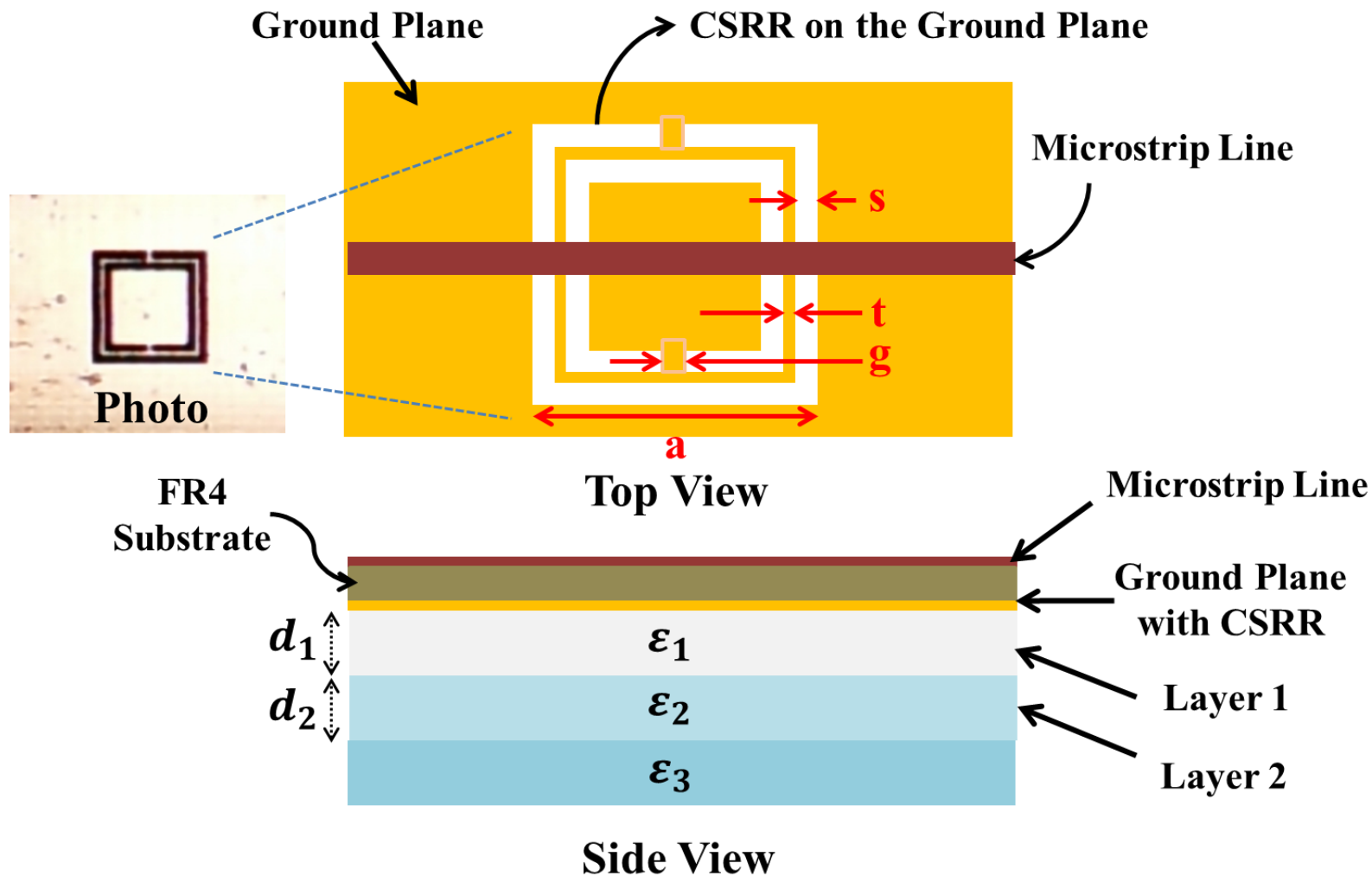
博班研究精華

題目：

**Measurement Thickness or Permittivity
Variations in Multilayered Dielectric Structures
by Using Complementary Split Ring Resonator**

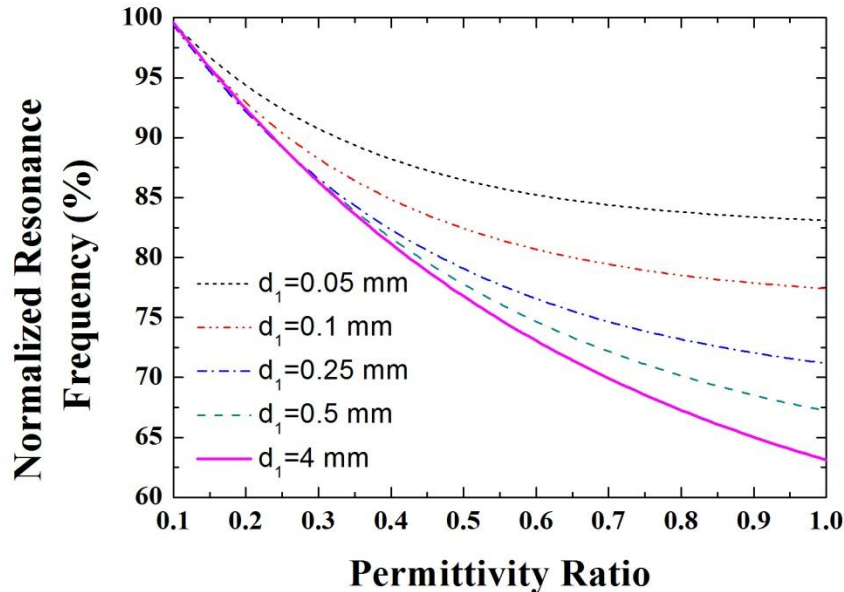
學生：杰森

CSRR detection multi-dielectric layer experimental setup



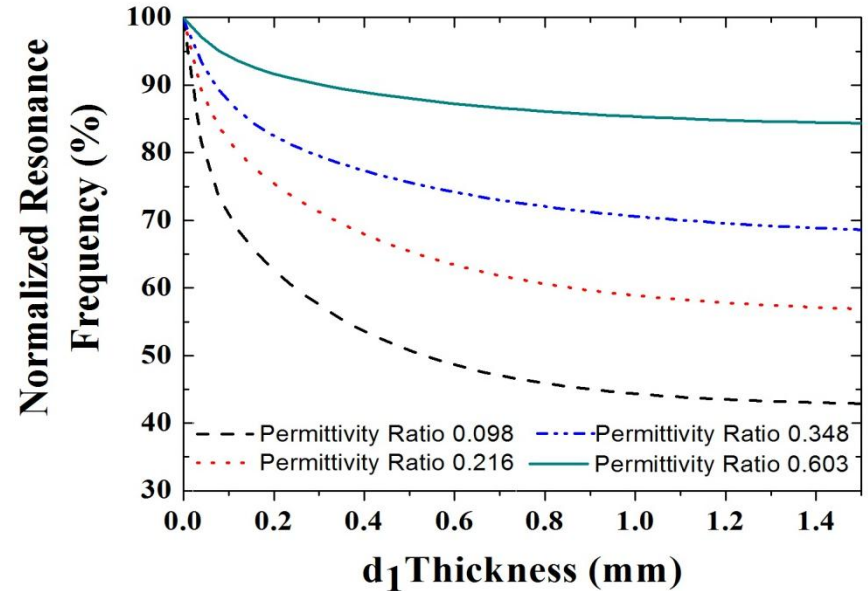
Analysis of the Sensor with Sample

Permittivity Variations



- Behavior the CSRR sensors as a function of dielectric ratio(ϵ_1/ϵ_2)
 - with $d_2=2$ mm, $\epsilon_2=10.2$ case.
- The shift resonance frequency of the sensors are normalized with respect to the resonance frequency when medium ϵ_1 is 1
 - for each $d_1=0.05$, 0.1 , 0.25 , 0.5 and 4 , six cases

Thickness Variations



- Behavior the CSRR sensors as a function of d_1 thickness
 - with $d_1 + d_2=4$ mm
- The shift resonance frequency of the sensors are normalized with respect to the resonance frequency when $d_1=0$ of the medium
 - in four different permittivity ration 0.098 , 0.216 , 0.348 , 0.603 cases

TABLE I.
CSRR DIMENSION FOR NUMERICAL ANALYSIS
 $t=g=0.2\text{mm}$

| | Case A | Case B | Case C | Case D | Case E |
|-------------------|--------|--------|--------|--------|--------|
| $a(\text{mm})$ | 3.5 | 6 | 13 | 6 | 6 |
| $s(\text{mm})$ | 0.4 | 0.4 | 0.4 | 0.2 | 0.7 |
| $f_o(\text{GHz})$ | 3.83 | 1.65 | 0.69 | 1.77 | 2.04 |

TABLE II.
PERMITTIVITY RESOLUTION ANALYSIS
 $d_1 + d_2 = 4\text{mm}$, $t=g=0.2\text{mm}$, $\epsilon_2=10.2$, $\Delta\epsilon_1=0.01$,

| $d_1(\text{mm})$ | 0.25 | | | 1.5 | | |
|------------------|-------|-------|-------|-------|-------|-------|
| ϵ_1 | 2.2 | 3.55 | 6.15 | 2.2 | 3.55 | 6.15 |
| Case A (%) | 0.035 | 0.019 | 0.010 | 0.063 | 0.047 | 0.031 |
| Case B (%) | 0.026 | 0.014 | 0.007 | 0.059 | 0.043 | 0.028 |
| Case C (%) | 0.022 | 0.012 | 0.006 | 0.057 | 0.040 | 0.026 |
| Case D (%) | 0.030 | 0.016 | 0.009 | 0.060 | 0.045 | 0.030 |
| Case E (%) | 0.026 | 0.014 | 0.007 | 0.059 | 0.043 | 0.028 |

TABLE III.
THICKNESS RESOLUTION ANALYSIS
 $d_1 + d_2 = 4\text{mm}$, $t=g=0.2\text{mm}$, $\epsilon_2=10.2$, $\Delta d_1=0.01$

| ϵ_1 | 3.55 | | | 6.15 | | |
|------------------|-------|-------|-------|-------|-------|-------|
| $d_1(\text{mm})$ | 0.05 | 0.25 | 1.5 | 0.05 | 0.25 | 1.5 |
| Case A (%) | 0.875 | 0.295 | 0.024 | 0.623 | 0.186 | 0.018 |
| Case B (%) | 0.652 | 0.288 | 0.028 | 0.451 | 0.179 | 0.022 |
| Case C (%) | 0.637 | 0.238 | 0.051 | 0.387 | 0.169 | 0.023 |
| Case D (%) | 0.711 | 0.283 | 0.026 | 0.499 | 0.186 | 0.022 |
| Case E (%) | 0.613 | 0.276 | 0.037 | 0.368 | 0.169 | 0.025 |

Conclusion

- A rectangular CSRR structure is etched out on the ground plane of a microstrip line as a sensor to measure thickness and dielectric of multi-layers was designed, fabricated and tested.
 - The sensor is based on the shift in the minimum transmission coefficient of the stop-band filter as a function
 - The optimized sensor design can provide better sensitivity in two thin cognate permittivity coincident layer.
- And the CSRR provide effective sensing and is easy integrated in microwave circuits